

ABSTRACT OF THE DISCLOSURE

There is provided a user-friendly quality assurance automatic display system which enables a user of semiconductor devices to readily ascertain correct quality assurance relating to the quality of semiconductor devices and to use the semiconductor devices in a carefree manner. Inspection item graded data—which have been graded by determination of reliability of a substance to be inspected for each inspection item—are held in an inspection item data hold section of a data processor. Inspection item graded data held in the inspection item data hold section are transported to a data processing section of the data processor. Subsequently, general graded data pertaining to the degree of quality assurance of the substance are determined in accordance with an algorithm employed in the data processing section. The general graded data determined by the data processing section are transported to a display device, where the general graded data are displayed on the display device.